
CERN 65nm IP blocks

AIDA Final Meeting – WP3.3
9th December 2014

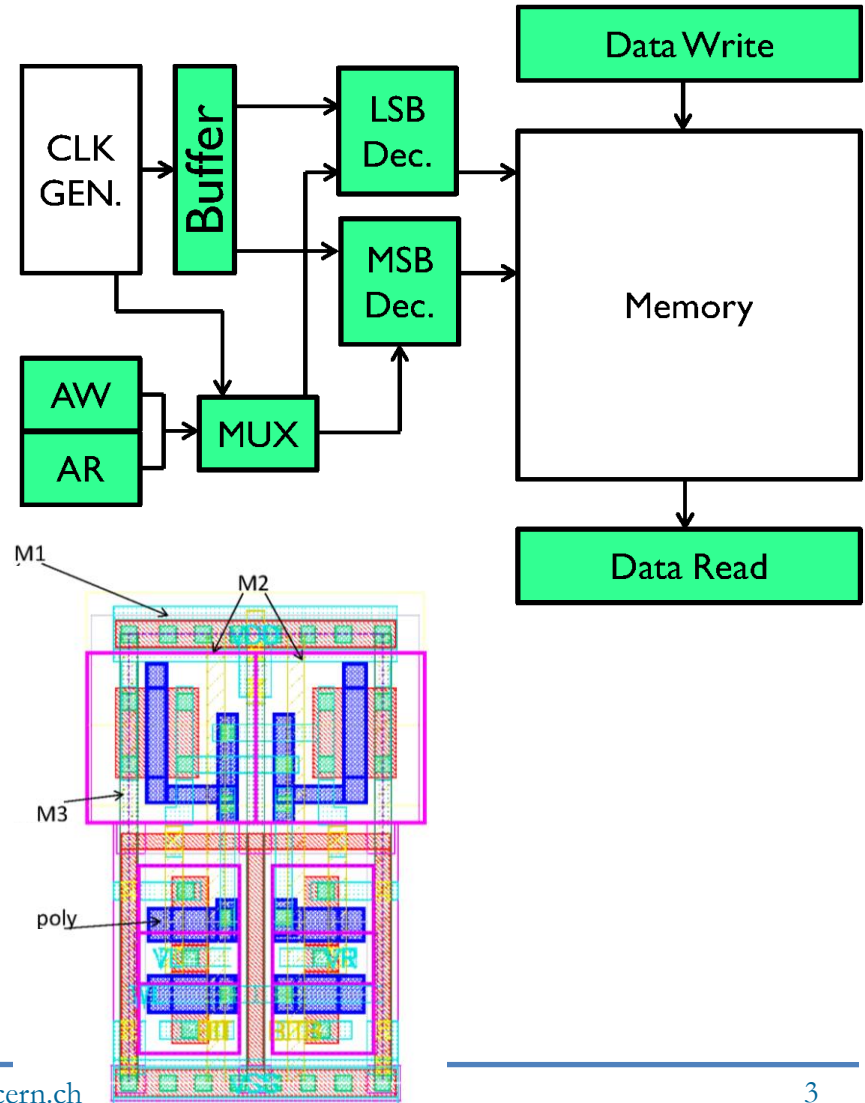
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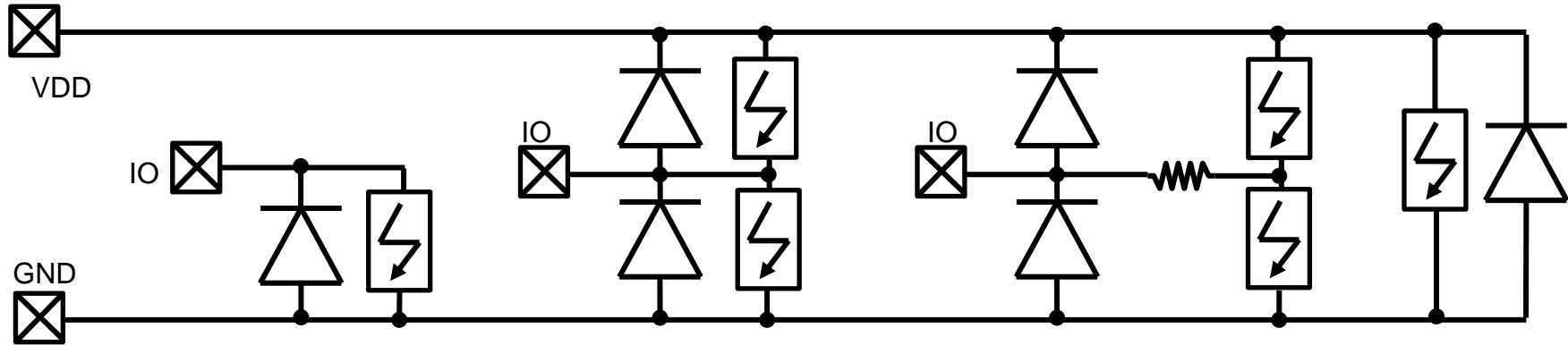


Rad-hard IP Blocks in 65nm

- SRAM compiler
- I/O pad library
- Monitoring ADC
- Bandgaps
- Rad-hard to 200Mrad according to specifications
- Deliverables
 - Schematic (OA)
 - Layout (OA)
 - Abstract (OA)
 - .lib (Liberty) capacitance limits and timing if applicable
 - Verilog / Verilog-AMS models
 - Datasheet

- Pseudo-dual-port (one read + one write in one clock cycle)
- 80 MHz operation
- Minimum size: 128 words of 8 bit
- Max size: 1k words of 256 bits
- Specifications on minimum W of transistors for radiation hardness
 - WPMOS>500nm, WNMOS>200nm
 - Cell size: 1.450 x 2.535 um²
- Part of the blocks are SET tolerant (in green in the figure)
 - If Hamming or other coding is used, SRAM becomes fully SEU tolerant
- Power consumption (simulated for a 1024x32 SRAM)
 - Read+write: 30 uW/MHz
 - Only read: 16 uW/MHz
 - Only write: 17 uW/MHz
 - Idle/static: 3 uW
- Test chip back from fabrication 21/11/2014
 - Silicon & radiation tests will follow
- Presented at AMICSA:
 - <https://indico.cern.ch/event/277669/session/5/contribution/12>

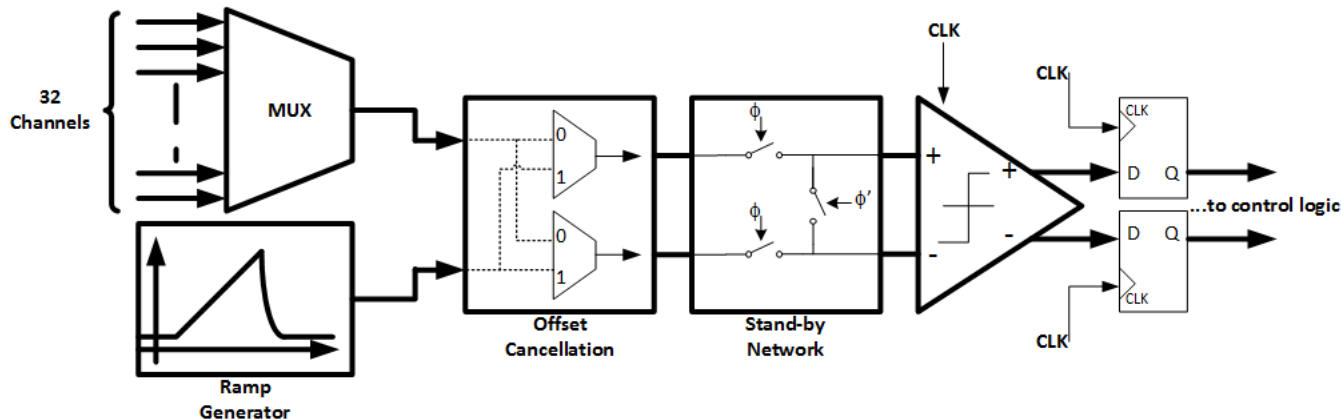




- Rated for 1.2V
- Only core devices, thin gate oxide
- Outsourced the development work for rad-hard ESD circuitry
 - Power clamps
 - Low-capacitance analog I/O (160 fF, 1 kV HBM ESD)
 - No connection to VDD/DVDD to avoid power supply noise
 - HBM+CDM ESD-protected I/O for digital (200fF, 2 kV ESD)
 - Delivered May 2014
- I/O drivers and receivers designed at CERN
 - Bidirectional digital CMOS I/O cell with slew-rate-controlled output
 - Driving strength control: 16 or 5 mA
 - Enable-controlled pull-up/down resistors (40kohm)

- ADC
 - Outsourced to Sparkling IC
 - 12 bit, 32 channels, single-slope
 - Temperature range -30 C to 80 C
 - Sampling rate 1 kS/s
 - power <500uW
 - input max slew rate 1 V/s
 - Wishbone digital interface (commands and I/O via registers)
- Digital logic implemented at CERN
- Test chip back from fabrication
 - Test board design in progress

Parameter	Value		
# of channels	32		
Resolution	12 bits		
Input Range	0V ÷ 800 mV		
Quantization Error (max)	< 1.5 LSB		
Noise _{0.1Hz ÷ 1GHz}	Input	Ramp	Comp
	117 μV	145 μV	138 μV
Power Consumption (max) (Analog Only)	≈ 400 μW		
Conversion Time (max)	≈ 430 μs		
Supply Voltage	1.2V ± 10%		
Area	0.163 mm ² (analog part only)		

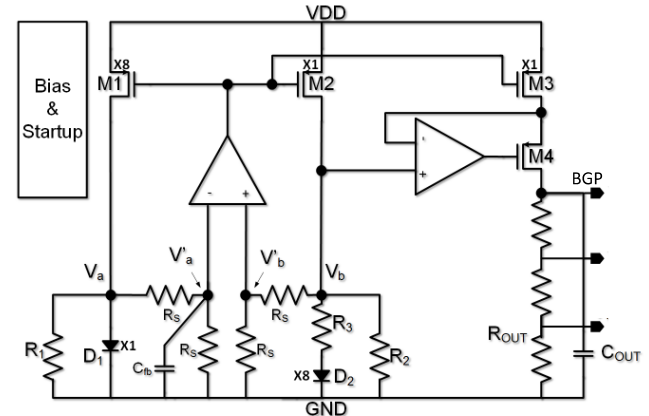


IP Block name:

CERN Bandgap V1 diode

Parameter	Size
Dimension	160x520um ²
Bandgap voltage	330mV
Required supply voltage	1.08-1.32V
Power consumption	200uW
Temperature range optimization	-20C +50C
Max variation (process, T, mismatch, corners)	3.2%
Min PSRR	-20dB @100KHz
Capacitor used	Momcap (for compatibility with all possible metal stacks)
Active element used	Diode between bulk and source of an ELT Pmos (to have gate oxide around the diode instead of STI)
Designers	Tommaso Vergine, Stefano Michelis
Status	Back from fabrication, test will follow
Schedule	Submission in September-October with Pavia/Bergamo and CPPM bandgaps

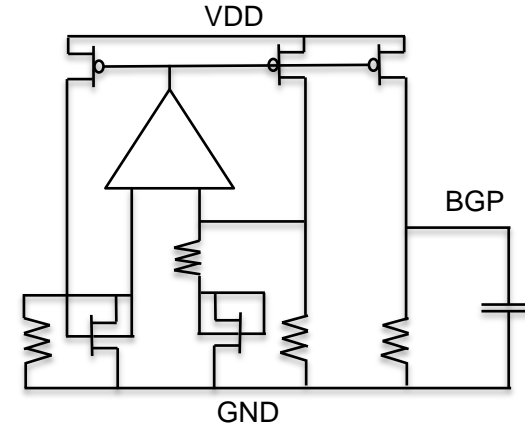
Block Diagram



I/O signals	Function
BGP	Bandgap output
VDD	Supply voltage
GND	Ground

IP Block name:**CERN Bandgap V2 DTNMOS**

Parameter	Size
Dimension	layout to be done
Bandgap voltage	300mV
Required supply voltage	1.08-1.32V
Power consumption	50uW
Temperature range optimization	-20C +50C
Max variation (process, T, mismatch, corners)	6-8% (models to be trusted?)
Min PSRR	-30dB @1MHz
Capacitor used	Momcap (for compatibility with all possible metal stacks)
Active element used	DTNMOS (NMOS biased in weak inversion to have the exponential behavior of diode)
Designers	Tommaso Vergine, Stefano Michelis
Status	Back from fabrication, test will follow
Schedule	Submission in September-October with Pavia/Bergamo and CPPM bandgaps

Block Diagram

I/O signals	Function
BGP	Bandgap output
VDD	Supply voltage
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Thank You



Backup Slides



Foundry IP library

- Foundry provides a wide range of IP blocks
 - Electrical fuse blocks / NVM
 - PLLs
 - 100MHz – 1600MHz
 - Jitter enhancement
 - Specialty I/O
 - USB 2.0 / UTMI+
 - DDR2 (up to 800Mbps), DDR1 (up to 533 Mbps)
 - Crystal oscillator, 32kHz
 - ROM compiler
 - Register File compiler
 - Single- and dual-port
 - SRAM compiler
 - Single-port and dual-port
 - Low-power and low-leakage

- Not made / not tested for radiation performance



Soft IP blocks

- I2C slave
 - 7- and 10-bit addressing

- HDLC communication protocol
 - Variable bit-rate
 - Average 7% bandwidth overhead

- 7b8b communication protocol
 - DC balanced
 - Fixed latency
 - Control characters available